



CMOS Static RAM 1 Meg (64K x 16-Bit)

IDT71016

Features

- ◆ 64K x 16 advanced high-speed CMOS Static RAM
- ◆ Equal access and cycle times
 - Commercial and Industrial: 12/15/20ns
- ◆ One Chip Select plus one Output Enable pin
- ◆ Bidirectional data inputs and outputs directly TTL-compatible
- ◆ Low power consumption via chip deselect
- ◆ Upper and Lower Byte Enable Pins
- ◆ Commercial and industrial product available in 44-pin Plastic SOJ package and 44-pin TSOP package

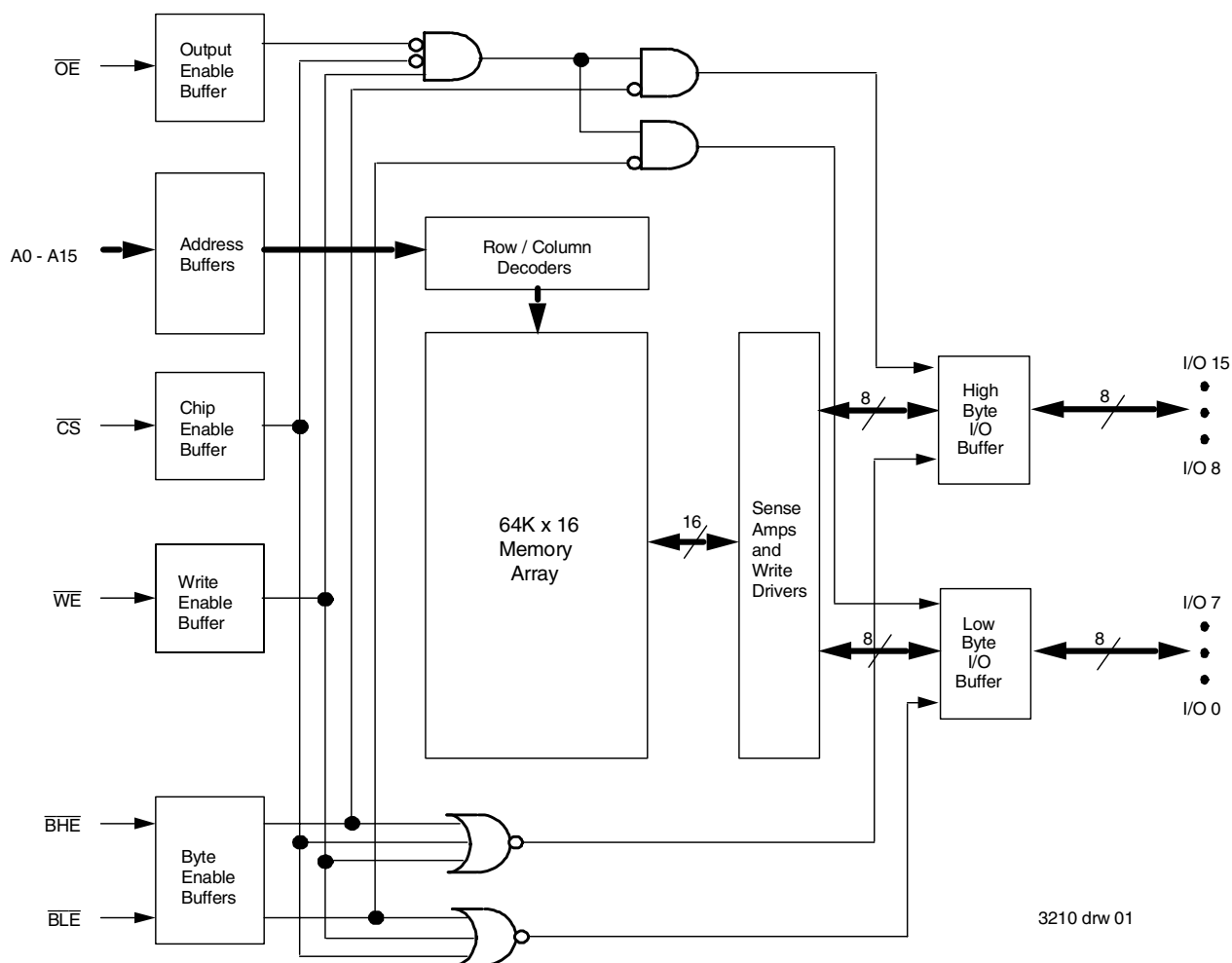
Description

The IDT71016 is a 1,048,576-bit high-speed Static RAM organized as 64K x 16. It is fabricated using IDT's high-performance, high-reliability CMOS technology. This state-of-the-art technology, combined with innovative circuit design techniques, provides a cost-effective solution for high-speed memory needs.

The IDT71016 has an output enable pin which operates as fast as 7ns, with address access times as fast as 12ns. All bidirectional inputs and outputs of the IDT71016 are TTL-compatible and operation is from a single 5V supply. Fully static asynchronous circuitry is used, requiring no clocks or refresh for operation.

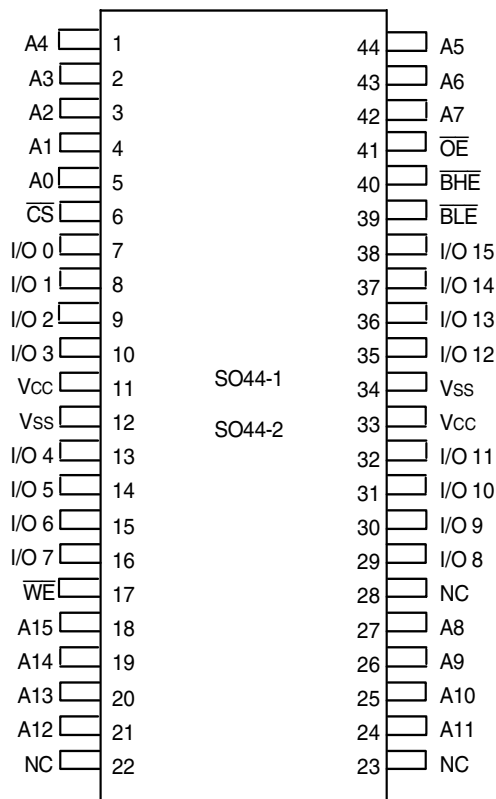
The IDT71016 is packaged in a JEDEC standard 44-pin Plastic SOJ and 44-pin TSOP Type II.

Functional Block Diagram



JANUARY 2004

Pin Configurations



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SOJ/TSOP Top View

Pin Descriptions

A0 - A15	Address Inputs	Input
$\overline{CS}$	Chip Select	Input
$\overline{WE}$	Write Enable	Input
$\overline{OE}$	Output Enable	Input
$\overline{BHE}$	High Byte Enable	Input
$\overline{BLE}$	Low Byte Enable	Input
I/O0 - I/O15	Data Input/Output	I/O
Vcc	5.0V Power	Pwr
Vss	Ground	Gnd

3210 tbl 01

Truth Table ⁽¹⁾

$\overline{CS}$	$\overline{OE}$	$\overline{WE}$	$\overline{BLE}$	$\overline{BHE}$	I/O0 - I/O7	I/O8 - I/O15	Function
H	X	X	X	X	High-Z	High-Z	Deselected - Standby
L	L	H	L	H	DATAOUT	High-Z	Low Byte Read
L	L	H	H	L	High-Z	DATAOUT	High Byte Read
L	L	H	L	L	DATAOUT	DATAOUT [*]	Word Read
L	X	L	L	L	DATAIN	DATAIN	Word Write
L	X	L	L	H	DATAIN	High-Z	Low Byte Write
L	X	L	H	L	High-Z	DATAIN	High Byte Write
L	H	H	X	X	High-Z	High-Z	Outputs Disabled
L	X	X	H	H	High-Z	High-Z	Outputs Disabled

NOTE:

1. H = V_{IH} , L = V_{IL} , X = Don't care.

3210 tbl 02

Absolute Maximum Ratings⁽¹⁾

Symbol	Rating	Value	Unit
V _{TERM} ⁽²⁾	Terminal Voltage with Respect to GND	-0.5 to +7.0	V
T _A	Operating Temperature	0 to +70	°C
T _{BIAS}	Temperature Under Bias	-55 to +125	°C
T _{STG}	Storage Temperature	-55 to +125	°C
P _T	Power Dissipation	1.25	W
I _{OUT}	DC Output Current	50	mA

3210 tbl 03

NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- V_{TERM} must not exceed V_{CC} + 0.5V.

Recommended Operating Temperature and Supply Voltage

Grade	Temperature	GND	V _{CC}
Commercial	0°C to +70°C	0V	5.0V ± 10%
Industrial	-40°C to +85°C	0V	5.0V ± 10%

3210 tbl 04

Recommended DC Operating Conditions

Symbol	Parameter	Min.	Typ.	Max.	Unit
V _{CC}	Supply Voltage	4.5	5.0	5.5	V
GND	Ground	0	0	0	V
V _{IH}	Input High Voltage	2.2	—	V _{DD} + 0.5	V
V _{IL}	Input Low Voltage	-0.5 ⁽¹⁾	—	0.8	V

NOTE:

3210 tbl 05

- V_{IL} (min.) = -1.5V for pulse width less than t_{RC}/2, once per cycle.

Capacitance

(T_A = +25° C, f = 1.0MHz, SOJ Package)

Symbol	Parameter ⁽¹⁾	Conditions	Max.	Unit
C _{IN}	Input Capacitance	V _{IN} = 3dV	6	pF
C _{I/O}	I/O Capacitance	V _{OUT} = 3dV	7	pF

NOTE:

3210 tbl 06

- This parameter is guaranteed by device characterization, but not production tested.

DC Electrical Characteristics

(V_{CC} = 5.0V ± 10%, Commercial and Industrial Temperature Range)

Symbol	Parameter	Test Conditions	Min.	Max.	Unit
I _{LI}	Input Leakage Current	V _{CC} = Max., V _{IN} = GND to V _{CC}	—	5	μA
I _{LO}	Output Leakage Current	V _{CC} = Max., $\overline{CS}$ = V _{IH} , V _{OUT} = GND to V _{CC}	—	5	μA
V _{OL}	Output Low Voltage	I _{OL} = 8mA, V _{CC} = Min.	—	0.4	V
V _{OH}	Output High Voltage	I _{OH} = -4mA, V _{CC} = Min.	2.4	—	V

3210 tbl 07

DC Electrical Characteristics⁽¹⁾

(V_{CC} = 5.0V ± 10%, V_{LC} = 0.2V, V_{HC} = V_{CC} - 0.2V)

Symbol	Parameter	71016S12		71016S15		71016S20		Unit
		Com'l.	Ind.	Com'l.	Ind.	Com'l.	Ind.	
I _{CC}	Dynamic Operating Current $\overline{CS} \leq V_{IL}$, Outputs Open, V _{CC} = Max., f = f _{MAX} ⁽²⁾	210	210	180	180	170	170	mA
I _{SB}	Standby Power Supply Current (TTL Level) $\overline{CS} \geq V_{IH}$, Outputs Open, V _{CC} = Max., F = f _{MAX} ⁽²⁾	60	60	50	50	45	45	mA
I _{SB1}	Standby Power Supply Current (CMOS Level) $\overline{CS} \geq V_{HC}$, Outputs Open, V _{CC} = Max., f = 0 ⁽²⁾ V _{IN} ≤ V _{LC} or V _{IN} ≥ V _{HC}	10	10	10	10	10	10	mA

NOTES:

3210 tbl 08

- All values are maximum guaranteed values.
- f_{MAX} = 1/t_{RC} (all address inputs are cycling at f_{MAX}); f = 0 means no address input lines are changing.

AC Test Conditions

Input Pulse Levels	GND to 3.0V
Input Rise/Fall Times	1.5ns
Input Timing Reference Levels	1.5V
Output Reference Levels	1.5V
AC Test Load	See Figure 1, 2 and 3

3210 tbl 09

AC Test Loads

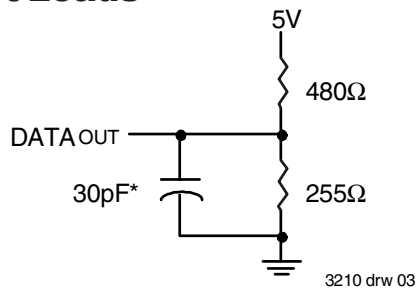


Figure 1. AC Test Load

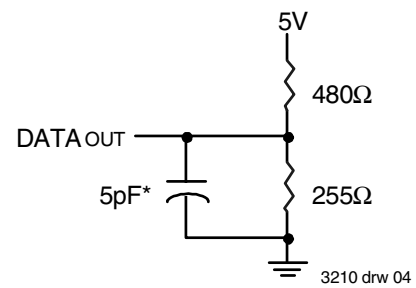


Figure 2. AC Test Load
(for tCLZ, tOLZ, tCHZ, tOHZ, tOW, and tWHZ)

*Including jig and scope capacitance.

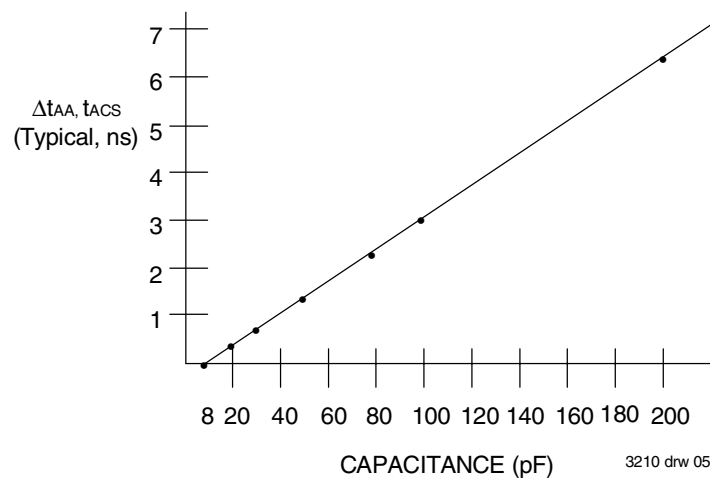


Figure 3. Output Capacitive Derating

AC Electrical Characteristics (V_{CC} = 5.0V ± 10%, Commercial and Industrial Range)

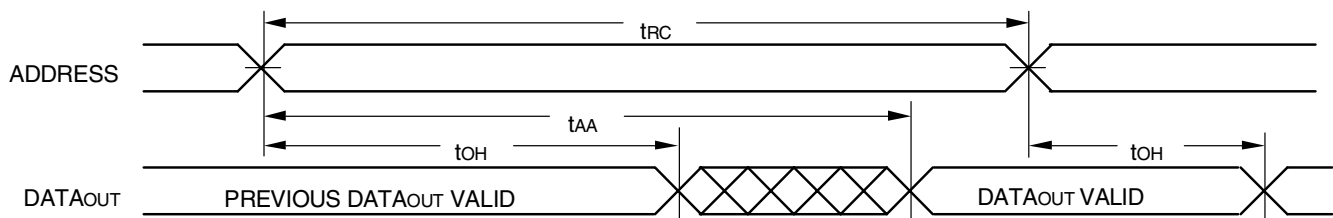
Symbol	Parameter	71016S12		71016S15		71016S20		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
READ CYCLE								
tRC	Read Cycle Time	12	—	15	—	20	—	ns
tAA	Address Access Time	—	12	—	15	—	20	ns
tACS	Chip Select Access Time	—	12	—	15	—	20	ns
tCLZ ⁽¹⁾	Chip Select Low to Output in Low-Z	4	—	5	—	5	—	ns
tCHZ ⁽¹⁾	Chip Select High to Output in High-Z	—	6	—	6	—	8	ns
tOE	Output Enable Low to Output Valid	—	7	—	8	—	10	ns
tOLZ ⁽¹⁾	Output Enable Low to Output in Low-Z	0	—	0	—	0	—	ns
tOHZ ⁽¹⁾	Output Enable High to Output in High-Z	—	6	—	6	—	8	ns
tOH	Output Hold from Address Change	4	—	4	—	5	—	ns
tBE	Byte Enable Low to Output Valid	—	7	—	8	—	10	ns
tBLZ ⁽¹⁾	Byte Enable Low to Output in Low-Z	0	—	0	—	0	—	ns
tBHZ ⁽¹⁾	Byte Enable High to Output in High-Z	—	6	—	6	—	8	ns
WRITE CYCLE								
tWC	Write Cycle Time	12	—	15	—	20	—	ns
tAW	Address Valid to End of Write	9	—	10	—	12	—	ns
tCW	Chip Select Low to End of Write	9	—	10	—	12	—	ns
tBW	Byte Enable Low to End of Write	9	—	10	—	12	—	ns
tAS	Address Set-up Time	0	—	0	—	0	—	ns
tWR	Address Hold from End of Write	0	—	0	—	0	—	ns
tWP	Write Pulse Width	9	—	10	—	12	—	ns
tDW	Data Valid to End of Write	7	—	8	—	10	—	ns
tDH	Data Hold Time	0	—	0	—	0	—	ns
tOW ⁽¹⁾	Write Enable High to Output in Low-Z	1	—	1	—	1	—	ns
tWHZ ⁽¹⁾	Write Enable Low to Output in High-Z	—	6	—	6	—	8	ns

3210 tbl 10

NOTE:

1. This parameter is guaranteed with the AC Load (Figure 2) by device characterization, but is not production tested.

Timing Waveform of Read Cycle No. 1^(1,2,3)

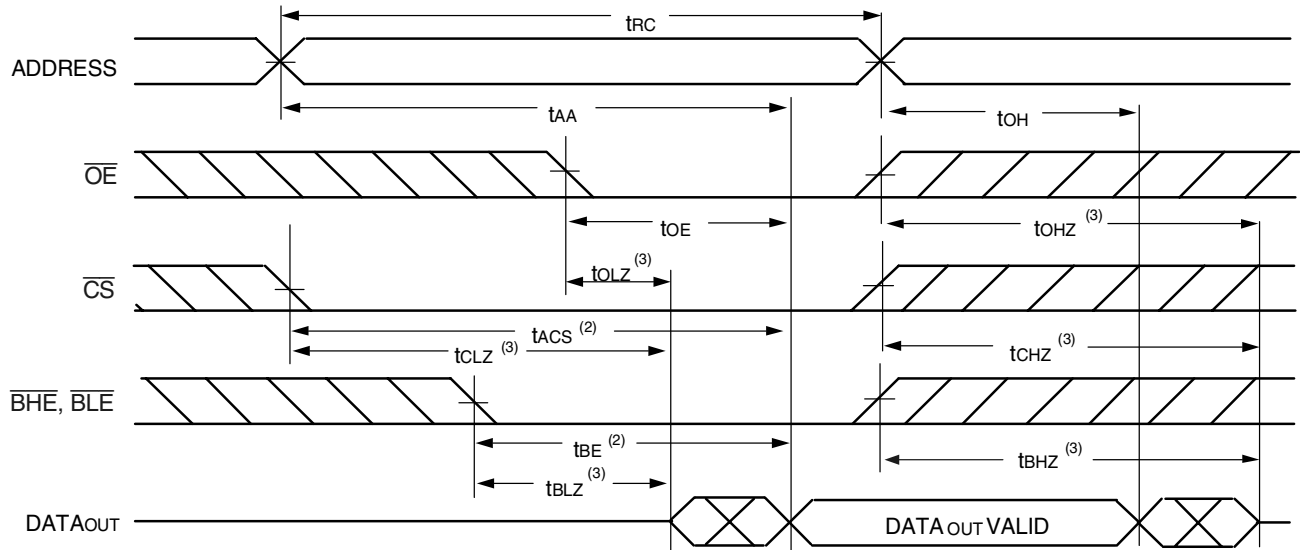


NOTES:

1. $\overline{WE}$ is HIGH for Read Cycle.
2. Device is continuously selected, $\overline{CS}$ is LOW.
3. $\overline{OE}$, $\overline{BHE}$, and $\overline{BLE}$ are LOW.

3210 drw 06

Timing Waveform of Read Cycle No. 2⁽¹⁾

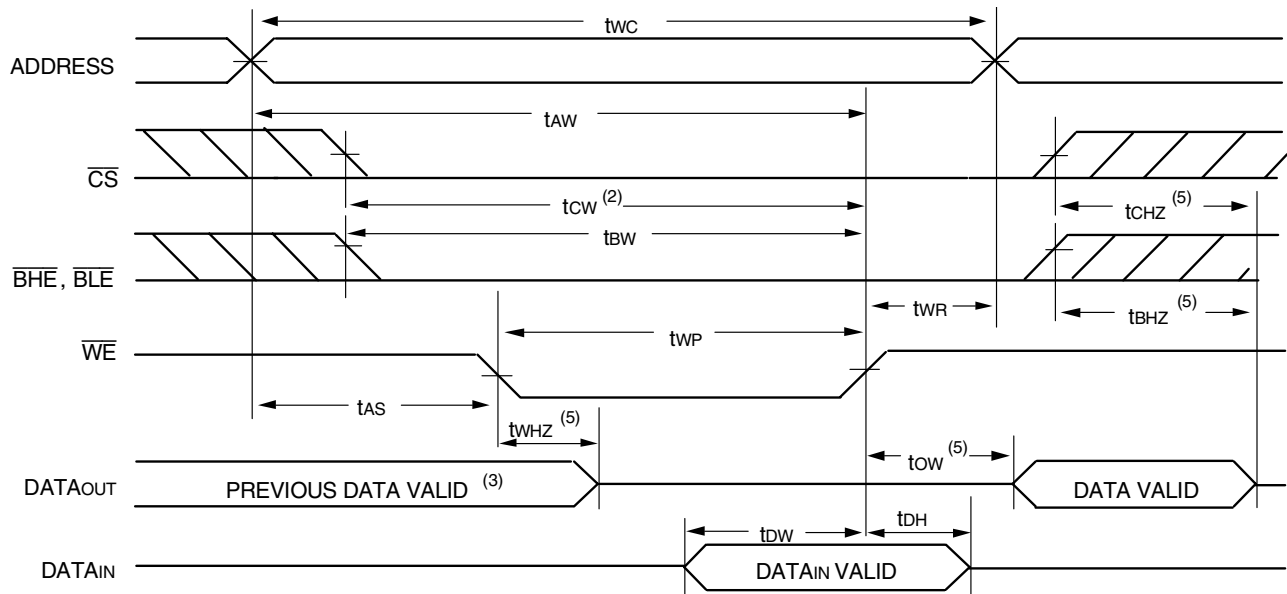


NOTES:

1. $\overline{WE}$ is HIGH for Read Cycle.
2. Address must be valid prior to or coincident with the later of $\overline{CS}$, $\overline{BHE}$, or $\overline{BLE}$ transition LOW; otherwise t_{AA} is the limiting parameter.
3. Transition is measured $\pm 200\text{mV}$ from steady state.

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Timing Waveform of Write Cycle No. 1 ($\overline{WE}$ Controlled Timing)^(1,2,4)



NOTES:

1. A write occurs during the overlap of a LOW $\overline{CS}$, LOW $\overline{BHE}$ or $\overline{BLE}$, and a LOW $\overline{WE}$.
2. $\overline{OE}$ is continuously HIGH. If during a $\overline{WE}$ controlled write cycle $\overline{OE}$ is LOW, t_{WP} must be greater than or equal to $t_{WHZ} + t_{DW}$ to allow the I/O drivers to turn off and data to be placed on the bus for the required t_{OW} . If $\overline{OE}$ is HIGH during a $\overline{WE}$ controlled write cycle, this requirement does not apply and the minimum write pulse is as short as the specified t_{WP} .
3. During this period, I/O pins are in the output state, and input signals must not be applied.
4. If the $\overline{CS}$ LOW or $\overline{BHE}$ and $\overline{BLE}$ LOW transition occurs simultaneously with or after the $\overline{WE}$ LOW transition, the outputs remain in a high-impedance state.
5. Transition is measured $\pm 200\text{mV}$ from steady state.

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The diagram illustrates the timing relationships for a memory access cycle. The signals and their timing parameters are as follows:

- ADDRESS:** Valid for t_{WC} (Write Cycle time).
- $\overline{CS}$:** Chip select signal. Valid for t_{AW} (Address Valid time) and t_{AS} (Address Setup time).
- $\overline{BHE}, \overline{BLE}$:** Data bus enable signals. Valid for t_{BW} (Data Valid time) and t_{WP} (Data Valid time).
- $\overline{WE}$:** Write enable signal. Valid for t_{WR} (Write Enable time).
- DATAout:** Data output signal. Valid for t_{DW} (Data Valid time) and t_{DH} (Data Hold time).
- DATAin:** Data input signal. Valid for t_{DW} (Data Valid time) and t_{DH} (Data Hold time).

Additional timing parameters shown include $t_{CW}^{(2)}$ (Write Cycle time) and t_{AS} (Address Setup time).

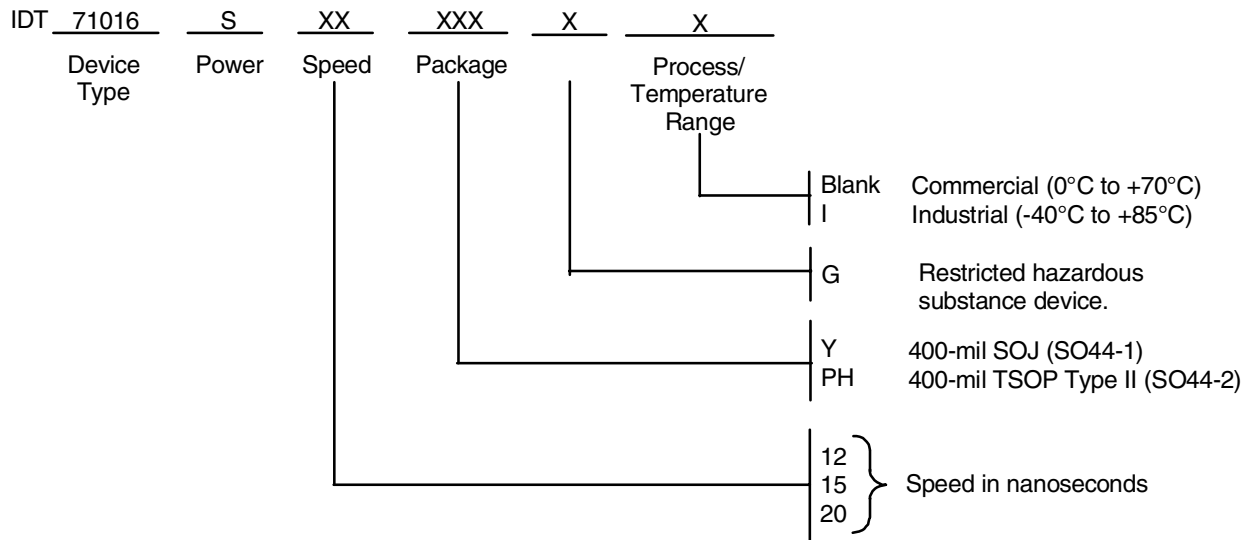
The diagram illustrates the timing relationships for a memory access operation. The signals and their timing parameters are as follows:

- ADDRESS:** The address bus signal. The total time from the first clock edge to the last is labeled t_{WC} .
- $\overline{CS}$:** The chip select signal. The time from the first clock edge to the last is labeled t_{AW} .
- $\overline{BHE}, \overline{BLE}$:** The bus enable signals. The time from the first clock edge to the last is labeled t_{AS} . The time from the last clock edge to the first is labeled $t_{CW}^{(2)}$. The time from the first clock edge to the last is labeled t_{BW} .
- $\overline{WE}$:** The write enable signal. The time from the first clock edge to the last is labeled t_{WP} . The time from the last clock edge to the first is labeled t_{WR} .
- DATAout:** The data bus output signal.
- DATAin:** The data bus input signal. The time from the first clock edge to the last is labeled t_{DW} . The time from the last clock edge to the first is labeled t_{DH} .

The diagram also shows the **DATAin VALID** period, which is the time during which the data input is valid.

1. A write occurs during the overlap of a LOW $\overline{CS}$, LOW $\overline{BHE}$ or $\overline{BLE}$, and a LOW $\overline{WE}$.
2. $\overline{OE}$ is continuously HIGH. If during a $\overline{WE}$ controlled write cycle $\overline{OE}$ is LOW, t_{WP} must be greater than or equal to $t_{WHZ} + t_{OW}$ to allow the I/O drivers to turn off and data to be placed on the bus for the required t_{OW} . If $\overline{OE}$ is HIGH during a $\overline{WE}$ controlled write cycle, this requirement does not apply and the minimum write pulse is as short as the specified t_{WP} .
3. During this period, I/O pins are in the output state, and input signals must not be applied.
4. If the $\overline{CS}$ LOW or $\overline{BHE}$ and $\overline{BLE}$ LOW transition occurs simultaneously with or after the $\overline{WE}$ LOW transition, the outputs remain in a high-impedance state.
5. Transition is measured $\pm 200\text{mV}$ from steady state.

Ordering Information



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Datasheet Document History

7/30/99		Updated to new format
8/5/99	Pg. 3	Expressed commercial and industrial ranges on DC Electrical table Removed I _{CC} , I _{SB} , and I _{SB1} values for S12 industrial speed
	Pg. 5	Expressed commercial and industrial ranges on AC Electrical table Changed footnote #2 to commercial temperature only
	Pg. 6	Revised footnotes on Write Cycle No. 1 diagram
	Pg. 7	Revised footnotes on Write Cycle No. 2 and No. 3 diagrams
	Pg. 8	Removed SCD 2752 footnote Added commercial only for 12ns speed
8/13/99	Pg. 9	Added Datasheet Document History
9/30/99	Pg. 3, 5, 8	Added 12ns industrial temperature speed grade offering
08/09/00		Not recommended for new designs
02/01/01		Removed "Not recommended for new designs"
01/30/04	Pg. 8	Added "Restricted hazardous substance device" to order information.



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